

Notice of References Cited

Application/Control No.

10/671,462

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

DAQUAN ZHAO

Art Unit

2621

Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,899,326 A	02-1990	Takeya et al.	369/30:83
*	B	US-4,962,494 A	10-1990	Kimura, Shigenobu	369/47.25
*	C	US-5,113,383 A	05-1992	Amemiya et al.	369/30.06
*	D	US-5,274,816 A	12-1993	Oka, Mayumi	713/2
*	E	US-5,448,741 A	09-1995	Oka, Mayumi	713/2
*	F	US-5,581,785 A	12-1996	Nakamura et al.	710/8
*	G	US-5,761,406 A	06-1998	Kobayashi et al.	714/24
*	H	US-5,825,649 A	10-1998	Yoshimura, Masahiko	700/82
*	T	US-5,862,107 A	01-1999	Goto, Souju	386/126
*	J	US-5,892,952 A	04-1999	Seko et al.	717/174
*	K	US-6,128,434 A	10-2000	Hirayama et al.	386/97
*	L	US-2001/0002223 A1	05-2001	WATANABE, KENICHI	386/75
*	M	US-6,288,991 B1	09-2001	Kajiyama et al.	369/47.23

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/671,462

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

DAQUAN ZHAO

Art Unit

2621

Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0040842 A1	11-2001	Yokota et al.	369/32
*	B	US-2002/0031065 A1	03-2002	Kajiyama et al.	369/47.23
*	C	US-2002/0072818 A1	06-2002	Moon et al.	700/94
*	D	US-2003/0039472 A1	02-2003	Kim, Doo-nam	386/126
*	E	US-2003/0086681 A1	05-2003	Miyagawa, Tamotsu	386/34
*	F	US-6,681,325 B1	01-2004	Marsh et al.	713/2
*	G	US-2004/0042763 A1	03-2004	Morita et al.	386/046
*	H	US-2004/0120228 A1	06-2004	Han, Gyoo Min	369/030.25
*	I	US-6,965,727 B1	11-2005	Sawabe et al.	386/96
*	J	US-7,085,477 B2	08-2006	Fujii et al.	386/96
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.